

**AMENDMENTS TO THE SPECIFICATION**

Please amend the Title on page 1 as follows:

**OPTICAL SEMICONDUCTOR DEVICE ENCODER**

Please amend the paragraph beginning at page 2, line 19, as follows:

That is, the patterns 34 which allow the light 36 pass therethrough, and the patterns 35 which shields the light, are provided by turns in the scale 33. The pitch of these patterns 34 and 35 matches substantially to the pitch of the photodiodes (1c, 1d, ...). For example, in the example expressed in this figure, the light and dark patterns 34 and 35 in the scale 33 match with one set of the photodiodes (1a-1d, 2a-2d).

Please amend the paragraph beginning at page 2, line 27, as follows:

The light 36 coming from the light emitting element ~~31~~ penetrates the scale 33, and goes into the photo-detecting device 32 with the light and dark patterns which are made by the light and dark patterns 34 and 35 in the scale.

Please amend the paragraph beginning at page 3, line 20, as follows:

However, the light also goes into the photodiodes under the dark pattern 35 which should be shielded from the light. Such a undesirable irradiation is caused by the influence of refraction and diffraction of the light 37 which penetrated the light pattern 34 of the scale 33, and/or by a circumference light. Therefore, such a DC component (OFS) is produced.